## Notice of References Cited Application/Control No. O9/963,689 Examiner Man Phan Applicant(s)/Patent Under Reexamination DENNEY ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A.	US-2003/0021237	01-2003	Min et al.	370/252
	В	US-2002/0131413	09-2002	Tsao et al.	370/392
	С	US-6,108,307	08-2000	McConnell et al.	370/235
	D	US-6,788,707	09-2004	Horton et al.	370/474
	E	US-2003/0035442	02-2003	Eng, John Wai Tsang	370/486
	F	US-5,983,315	11-1999	Larky et al.	711/109
	G	US-6,081,533	06-2000	Laubach et al.	370/421
	Н	US-6,028,860	02-2000	Laubach et al.	370/395.64
	ı	US-6,917,614	07-2005	Laubach et al.	370/392
	J	US-2002/0154655	10-2002	Gummalia et al.	370/468
	к	US-6,898,755	05-2005	Hou, Victor T.	714/784
	L	US-5,754,535	05-1998	Vandenabeele et al.	370/321
	М	US-6,546,017	04-2003	Khaunte, Sunil	370/412

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0		-			
	Р					·
	O.					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

HON-FATERY DOCUMENTO							
*	_	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
	×						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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